

Special Issue

Advanced Technologies and Methods in Mechanical Fault Diagnostics and Prognostics

Message from the Guest Editors

Fault diagnostics and prognostics play significant roles in ensuring the safe operation of mechanical systems. With the development of condition-based maintenance and predictive maintenance, fault diagnostics and prognostics have attracted increasing amounts of attention in both academic research and industrial practice. With this Special Issue, we aim to summarize and publish the advanced technologies and methods in mechanical fault diagnostics and prognostics. This Special Issue aims to provide a platform for scholars to publish their new ideas and research works in this area. Areas relevant to advanced technologies and methods in mechanical fault diagnostics and prognostics include, but are not limited to, the following:

- Dynamic modeling of mechanical systems;
- Degradation modeling of mechanical systems;
- Advanced signal processing technologies;
- Health indicator construction from multi-sensor signals;
- Health condition monitoring of mechanical systems;
- Big-data-driven intelligent fault diagnostics;
- Data-model-fusion fault diagnostics and prognostics;
- Remaining useful life prediction of mechanical systems.

Guest Editors

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Editor-in-Chief

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